

N- and P-Channel 30 V (D-S) MOSFET

PRODUCT SUMMARY							
	V _{DS} (V)	$R_{DS(on)}$ (m Ω)(Typ.)	I _D (A) ^a	Q _g (Typ.)			
N-Channel	30	9.5 at V _{GS} = 10 V	40	13.7 nC			
		16 at $V_{GS} = 4.5 \text{ V}$	7				
P-Channel	- 30	12.5 at V GS = - 10 V	- 30	28 nC			
		16 at V GS = - 4.5 V	- 30				

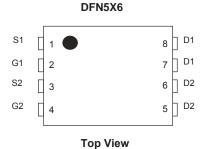
FEATURES

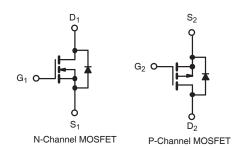
- DT-Trench Power MOSFET
- 100 % R_q and UIS tested
- Excellent Thermal Performance
- RoHS and Halogen Free Compliant



APPLICATIONS

- Motor Drive
- DC-FAN





ABSOLUTE MAXIMUM RATINGS (T _C = 25 °C, unless otherwise noted)						
PARAMETER	SYMBOL	N-Channel	P-Channel	UNIT		
Drain-Source Voltage	V _{DS}	30	- 30	V		
Gate-Source Voltage		V_{GS}	± 20		± 20	
Continuous Drain Current /T. 150° C\3	T _C = 25 °C	- I _D	40	- 30	А	
Continuous Drain Current (T _J = 150° C) ^a	T _C = 100 °C		25	- 19		
Pulsed Drain Current ^b	I _{DM}	140	- 105			
Maximum Power Dissipation ^C	T _C = 25 °C	- P _D	30	25	W	
Waxiiiuiii Fowei Dissipation-	T _C = 100 °C		12	10	VV	
Operating Junction and Storage Temperature Rang	T _J , T _{stg}	-55 to +150		90		
Soldering Recommendations (Peak Temperature)		260		°C		

THERMAL RESISTANCE RATINGS							
Parameter	Symbol	N-Channel P-Channel		Unit			
rai ailletei		Symbol	Max	Max	Oilit		
Maximum Junction-to-Ambient d	t ≤ 10 s	R _{thJA}	55	55 60 °C/W			
Maximum Junction-to-Case (Drain)	Steady State	R _{thJC}	4.16	5	C/VV		

Notes

- a. Calculated continuous current based on maximum allowablejunction temperature.
- b. Repetitive rating; pulse width limited by max. junction temperature.
- c. Pd is based on max. junction temperature, using junction-case thermal resistance.
- d. The value of $R_{\theta JA}$ is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper,in a still air environment with Ta=25 °C.



PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT	
Static							
Drain-Source Breakdown Voltage	V_{DS} $V_{GS} = 0 \text{ V}, I_D = 250 \mu A$		30	-	-	V	
Gate Threshold Voltage	V _{GS(th)}	$V_{GS(th)}$ $V_{DS} = V_{GS}$, $I_D = 250 \mu A$		-	3.0		
Gate-Body Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$	-	-	± 100	nA	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$			1	μА	
Zero Gate Voltage Drain Gunerit		V _{DS} = 24 V, V _{GS} = 0 V, T _J = 55 °C			10		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	40	-	-	Α	
Drain-Source On-State Resistance a	B-ac	V _{GS} = 10 V, I _D = 10 A	-	9.5	12	mΩ	
Diam-cource on-state nesistance	R _{DS(on)}	V _{GS} = 4.5 V, I _D = 8 A	-	16	20		
Forward Transconductance ^a	9 _{fs}	$V_{DS} = 5 \text{ V}, I_{D} = 10 \text{ A}$	-	43	-	S	
Dynamic ^b							
Input Capacitance	C _{iss}		-	660	-	pF	
Output Capacitance	C _{oss}	V _{GS} = 0 V, V _{DS} = 15 V, f = 1 MHz	-	100	-		
Reverse Transfer Capacitance	C _{rss}		-	85	-		
Total Gate Charge ^c	Qg		-	13.7	-	nC	
Gate-Source Charge ^c	Q _{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$	-	1.1	-		
Gate-Drain Charge ^c	Q_{gd}		-	2.7	-		
Gate Resistance	R _g	f = 1 MHz	-	3.2	-	Ω	
Turn-On Delay Time ^c	t _{d(on)}		-	6	-		
Rise Time ^c	t _r	$V_{DS} = 15 \text{ V}, I_{D} = 10 \text{ A}, R_{g} = 2.5 \Omega$	-	10	-	l	
Turn-Off Delay Time ^c	t _{d(off)}	V _{GS} = 10 V	-	18	-	- ns -	
Fall Time ^c	t _f		-	8	-		
Drain-Source Body Diode Ratings and	Characterist	ics ^b (T _C = 25 °C)		•			
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C	-	-	40	Α	
Pulsed Current (t = 100 μs)	I _{SM}		-	-	140	Α	
Forward Voltage ^a	V _{SD}	I _F = 1 A, V _{GS} = 0 V	-	-	1.2	V	
Reverse Recovery Time	t _{rr}	1 10 A di/dt 100 A/:-	-	7	-	ns	
Reverse Recovery Charge	Q _{rr}	I _F = 10 A, di/dt = 100 A/μs	_	9	_	nC	

Notes

- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.
- c. Independent of operating temperature.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT	
Static							
Drain-Source Breakdown Voltage	V_{DS} $V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$		- 30	-	-	V	
Gate Threshold Voltage	V _{GS(th)}	$V_{GS(th)}$ $V_{DS} = V_{GS}$, $I_D = -250 \mu A$		-	- 3.0	V	
Gate-Body Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$	-	-	± 100	nA	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = - 30 V, V _{GS} = 0 V	1		- 1		
Zero Gate Voltage Drain Gunerit		V _{DS} = - 24 V, V _{GS} = 0 V, T _J = 55 °C	-	-	- 10 μA		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \le -5$, $V_{GS} = -10 \text{ V}$	- 30	-	-	Α	
Drain-Source On-State Resistance a	B _{not} :	V _{GS} = - 10 V, I _D = - 8 A	-	12.5	16	mΩ	
Diam-Source On-State Hesistance	R _{DS(on)}	V _{GS} = - 4.5 V, I _D = - 8 A	-	16	20	11177	
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 5 V, I _D = - 8 A	-	38	-	S	
Dynamic ^b							
Input Capacitance	C _{iss}		-	2040	-	pF	
Output Capacitance	C _{oss}	V _{GS} = 0 V, V _{DS} = - 15 V, f = 1 MHz	-	250	-		
Reverse Transfer Capacitance	C _{rss}		-	237	-		
Total Gate Charge ^c	Qg		-	28	-	nC	
Gate-Source Charge ^c	Q _{gs}	V _{DS} = - 15 V, V _{GS} = - 10 V, I _D = - 8 A	-	4.5	-		
Gate-Drain Charge ^c	Q_{gd}		-	7.5	-		
Gate Resistance	R _g	f = 1 MHz	-	6.8	-	Ω	
Turn-On Delay Time ^c	t _{d(on)}		-	12	-		
Rise Time °	t _r	$V_{DS} = -15 \text{ V}, I_{D} = -8 \text{ A}, R_{g} = 2.5 \Omega$	-	8.5	-	- ns	
Turn-Off Delay Time ^c	t _{d(off)}	V _{GS} = - 10 V	-	45	-		
Fall Time ^c	t _f		-	19	-		
Drain-Source Body Diode Ratings and	Characterist	tics ^b (T _C = 25 °C)					
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C	-	-	- 30	Α	
Pulsed Current	I _{SM}		-	-	- 105	Α	
Forward Voltage ^a	V _{SD}	I _F = - 1 A, V _{GS} = 0 V	-	-	- 1.2	V	
Reverse Recovery Time	t _{rr}	I 0 A di/d+ 100 A/:	-	14	-	ns	
Reverse Recovery Charge	Q _{rr}	I _F = - 8 A, di/dt = 100 A/μs	-	18	-	nC	

Notes

- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.
- c. Independent of operating temperature.

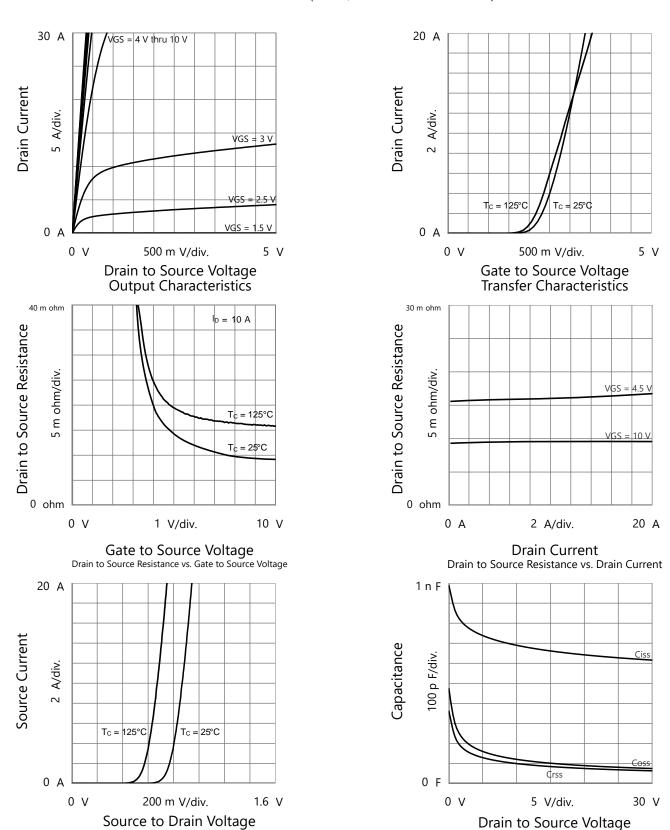
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N-CHANNEL TYPICAL CHARACTERISTICS (25°C, unless otherwise noted)

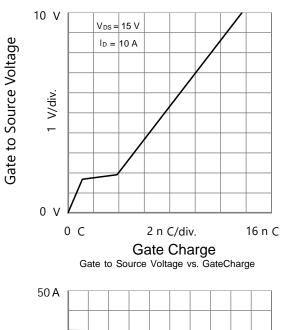
Body Diode Forward Characteristics

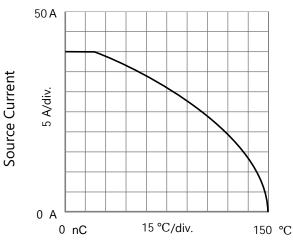


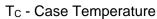
Capacitances

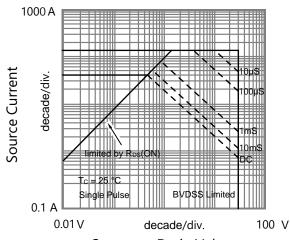


N-CHANNEL TYPICAL CHARACTERISTICS (25°C, unless otherwise noted)

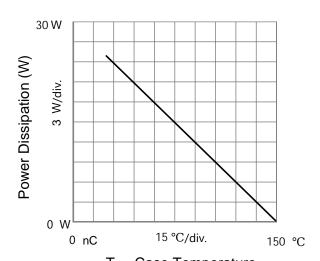




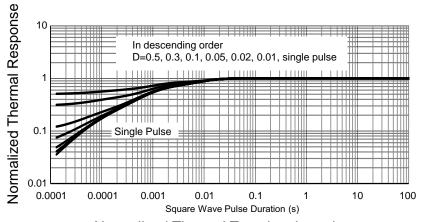




Source to Drain Voltage Safe Operating Area, Junction-to-Ambient



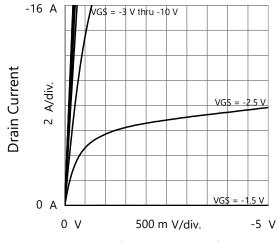
T_C - Case Temperature



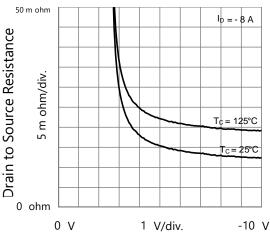
Normalized Thermal Transient Impedance



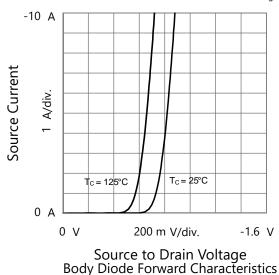
P-CHANNEL TYPICAL CHARACTERISTICS (25°C, unless otherwise noted)

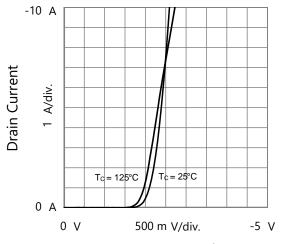


Drain to Source Voltage Output Characteristics

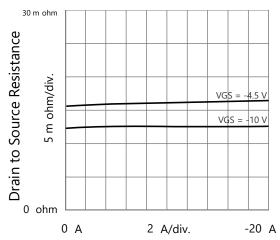


Gate to Source Voltage
Drain to Source Resistance vs. Gate to Source Voltage

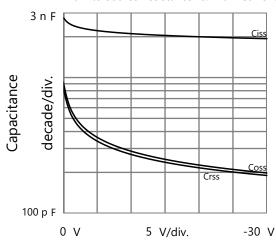




Gate to Source Voltage Transfer Characteristics



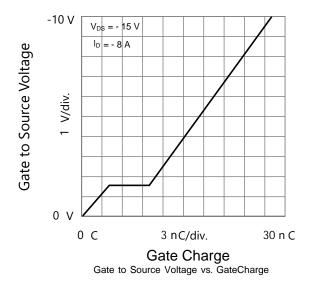
Drain Current
Drain to Source Resistance vs. Drain Current

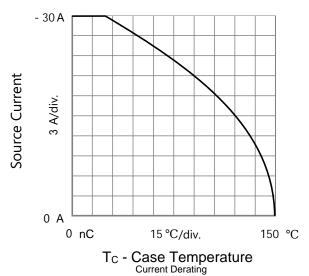


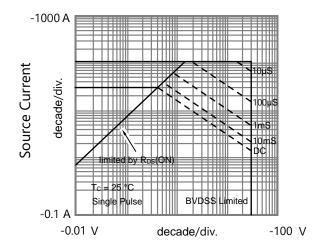
Drain to Source Voltage Capacitances



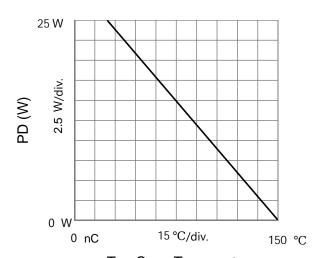
P-CHANNEL TYPICAL CHARACTERISTICS (25°C, unless otherwise noted)





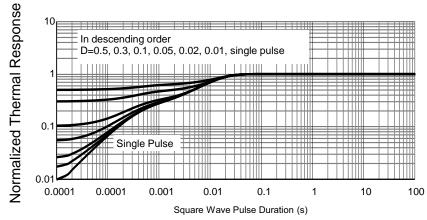


Source to Drain Voltage Safe Operating Area, Junction-to-Ambient



T_C - Case Temperature

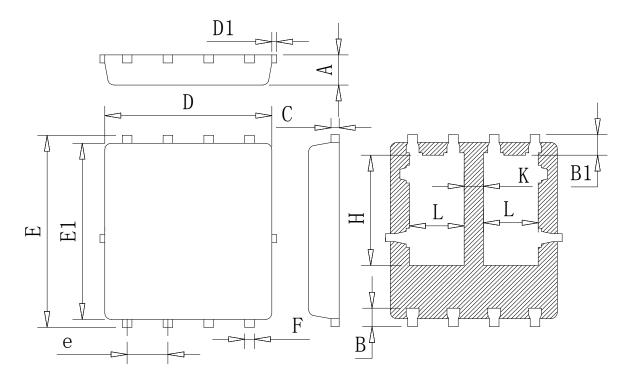
Power Derating



Normalized Thermal Transient Impedance

DFN5X6-8L-D PACKAGE OUTLINE

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COMMON DIMENSIONS (UNITS OF MEASURE=MILLIMETER)

Symbol	Min	Тур	Max
A	0.85	0.95	1.05
В	0.46	0.58	0.73
B1	0.52	0.65	0.78
С	0.18	0.254	0.32
D	4.70	5.20	5.50
D1	-	-	0.18
Е	5.75	6.05	6.35
E1	5.35	5.65	5.85
e	1.15	1.27	1.50
F	0.15	0.30	0.50
Н	3.15	3.47	3.80
L	1.35	1.70	2.10
K	0.35	0.60	1.00





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